

March 2013

## FCH76N60NF

# N-Channel SupreMOS® FRFET® MOSFET

**600 V, 72.8 A, 38 m**Ω

#### **Features**

- $R_{DS(on)} = 28.7 \text{ m}\Omega \text{ (Typ.)} @ V_{GS} = 10 \text{ V, } I_D = 38 \text{ A}$
- Ultra Low Gate Charge (Typ.Q<sub>a</sub> = 230 nC)
- Low Effective Output Capacitance (Typ. C<sub>oss</sub>.eff = 896 pF)
- 100% Avalanche Tested
- RoHS Compliant

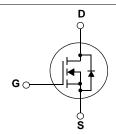
## **Applications**

- Solar Inverter
- AC-DC Power Supply

## **Description**

The SupreMOS® MOSFET is Fairchild Semiconductor®, s next-generation of high voltage super-junction (SJ) technology employing a deep trench filling process that differentiate it from the conventional MOSFETs. This advanced technology and precise process control provide lowest Rsp on-resistance, superior switching performance and ruggedness. SupreMOS MOSFET is suitable for high frequency switching power converter applications such as PFC, server/telecom power, FPD TV power, ATX power and industrial power applications. SupreMOS FRFET® MOSFET's optimized body diode reverse recovery performance can remove additional component and improve system reliability.





## MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol		Parameter		FCH76N60NF	Unit
V <sub>DSS</sub>	Drain to Source Voltage				V
V <sub>GSS</sub>	Gate to Source Voltage			±30	V
ı	Drain Current	-Continuous (T <sub>C</sub> = 25°C)		72.8	۸
I <sub>D</sub>	Drain Current	-Continuous (T <sub>C</sub> = 100°C)		46	A
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	218	Α
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		(Note 2)	7381	mJ
I <sub>AR</sub>	Avalanche Current			24.3	А
E <sub>AR</sub>	Repetitive Avalanche Energy			5.43	mJ
dv/dt	MOSFET dv/dt Ruggedness			100	V/ns
uv/ui	Peak Diode Recovery dv/dt		(Note 3)	50	V/11S
D	Power Dissipation	$(T_C = 25^{\circ}C)$		543	W
$P_{D}$	Fower Dissipation	- Derate above 25°C		4.34	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Tempera	ng and Storage Temperature Range		-55 to +150	οС
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C

<sup>\*</sup>Drain current limited by maximum junction temperature

## **Thermal Characteristics**

Symbol	Parameter	FCH76N60NF	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.23	
$R_{\theta CS}$	Thermal Resistance, Case to Heat Sink (Typical)	0.24	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	40	

## **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FCH76N60NF	FCH76N60NF	TO-247	=	=	30

## **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	eteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}, T_C = 25^{\circ}\text{C}$	600	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 1 mA, Referenced to 25°C	-	0.73	-	V/°C
ı	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 480 V, V <sub>GS</sub> = 0 V	-	-	10	^
IDSS	Zero Gate voltage Drain Current	$V_{DS} = 480 \text{ V}, V_{GS} = 0 \text{ V}, T_{C} = 125^{\circ}\text{C}$	-	-	100	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA

## **On Characteristics**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu\text{A}$	3.0	-	5.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 38 \text{ A}$	-	28.7	38.0	mΩ
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 20 \text{ V}, I_{D} = 38 \text{ A}$	-	92	-	S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	.,	-	8305	11045	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V f = 1 MHz		361	480	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			3.3	5.0	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 380 \text{ V}, V_{GS} = 0 \text{V}, f = 1 \text{ MHz}$	-	192	-	pF
C <sub>oss</sub> eff.	Effective Output Capacitance	$V_{DS} = 0 \text{ V to } 380 \text{ V}, V_{GS} = 0 \text{ V}$	-	896	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V		-	230	300	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DS} = 380 \text{ V}, I_{D} = 38 \text{ A},$	-	44	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 10 V (Note 4)	-	95	-	nC
ESR	Equivalent Series Resistance(G-S)	Drain Open	-	1.2	-	Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		-	51	112	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 380 \text{ V}, I_{D} = 38 \text{ A}$	-	44	98	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 4.7 \Omega$	-	213	436	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)	-	43	96	ns

#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current			-	76	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	228	Α
$V_{SD}$	Drain to Source Diode Forward Voltage V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 38 A		-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 38 A	-	200	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	-	1.8	-	μС

#### Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. I $_{AS}$  = 24.3 A, R $_{G}$  = 25  $\Omega$ , Starting T $_{J}$  = 25°C
- 3. I\_{SD}  $\leq$  72.8 A, di/dt  $\leq$  1200 A/µs, V\_DD  $\leq$  380 V, Starting T\_J = 25°C
- 4. Essentially Independent of Operating Temperature Typical Characteristics

## **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

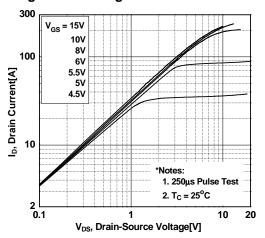


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

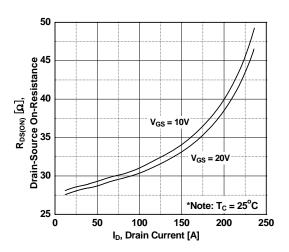


Figure 5. Capacitance Characteristics

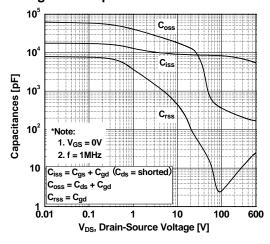


Figure 2. Transfer Characteristics

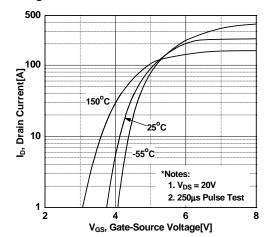


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

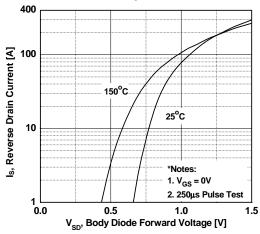
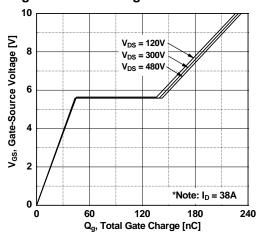


Figure 6. Gate Charge Characteristics



## **Typical Performance Characteristics (Continued)**

Figure 7. Breakdown Voltage Variation vs. Temperature

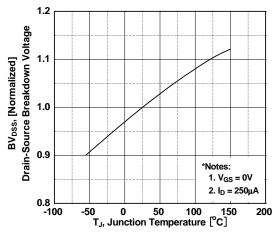


Figure 8. On-Resistance Variation vs. Temperature

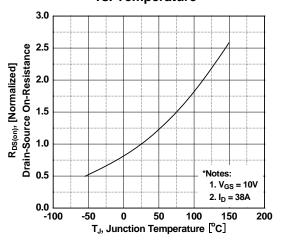


Figure 9. Maximum Safe Operating Area

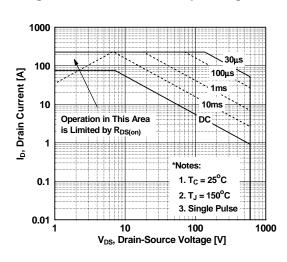


Figure 10. Maximum Drain Current vs. Case Temperature

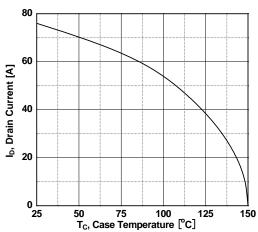
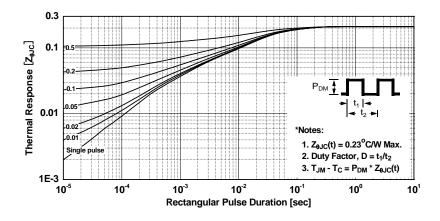
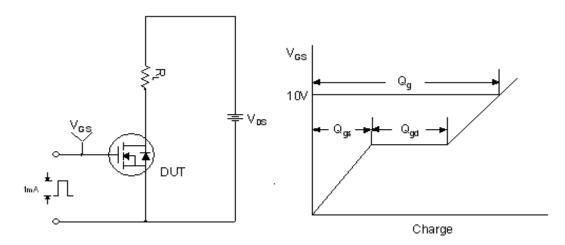


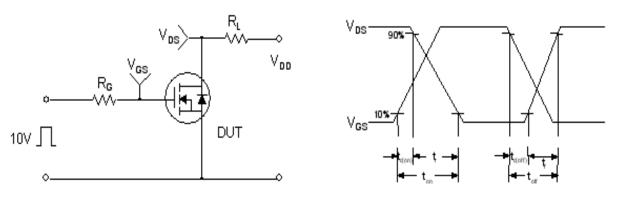
Figure 11. Transient Thermal Response Curve



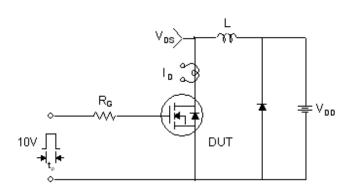
## **Gate Charge Test Circuit & Waveform**

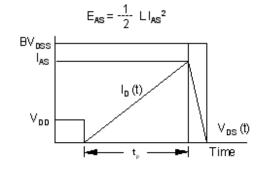


## **Resistive Switching Test Circuit & Waveforms**

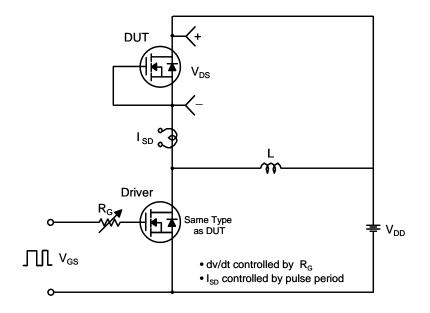


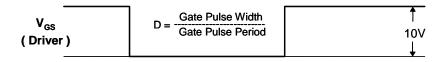
## **Unclamped Inductive Switching Test Circuit & Waveforms**

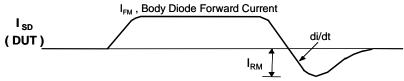




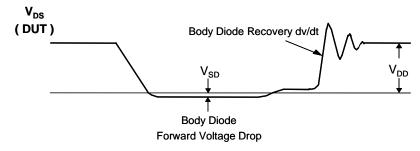
#### Peak Diode Recovery dv/dt Test Circuit & Waveforms





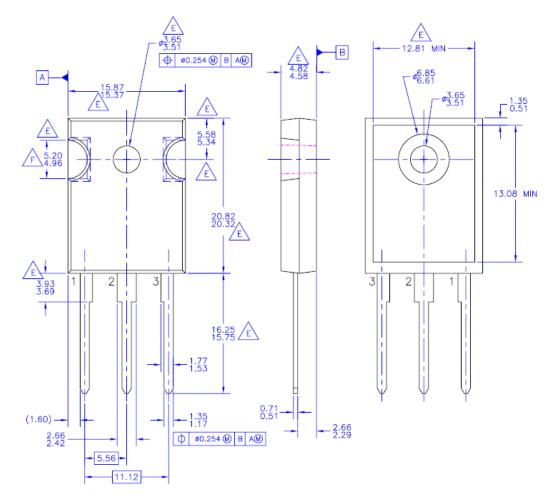


Body Diode Reverse Current



## **Mechanical Dimensions**

## TO-247-3L



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